

## ABSTRACT

METHOD AND APPARATUS FOR PERFORMING ATOMIC FORCE MICROSCOPY  
MEASUREMENTS

The present invention is related to a method and apparatus for performing Atomic Force Microscopy. In the method of the invention, a force profile is defined, and a sample is scanned by the AFM probe in such a way that the force between the sample and the probe is changed according to said predefined profile. The invention is equally related to an apparatus with which to perform said method.

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